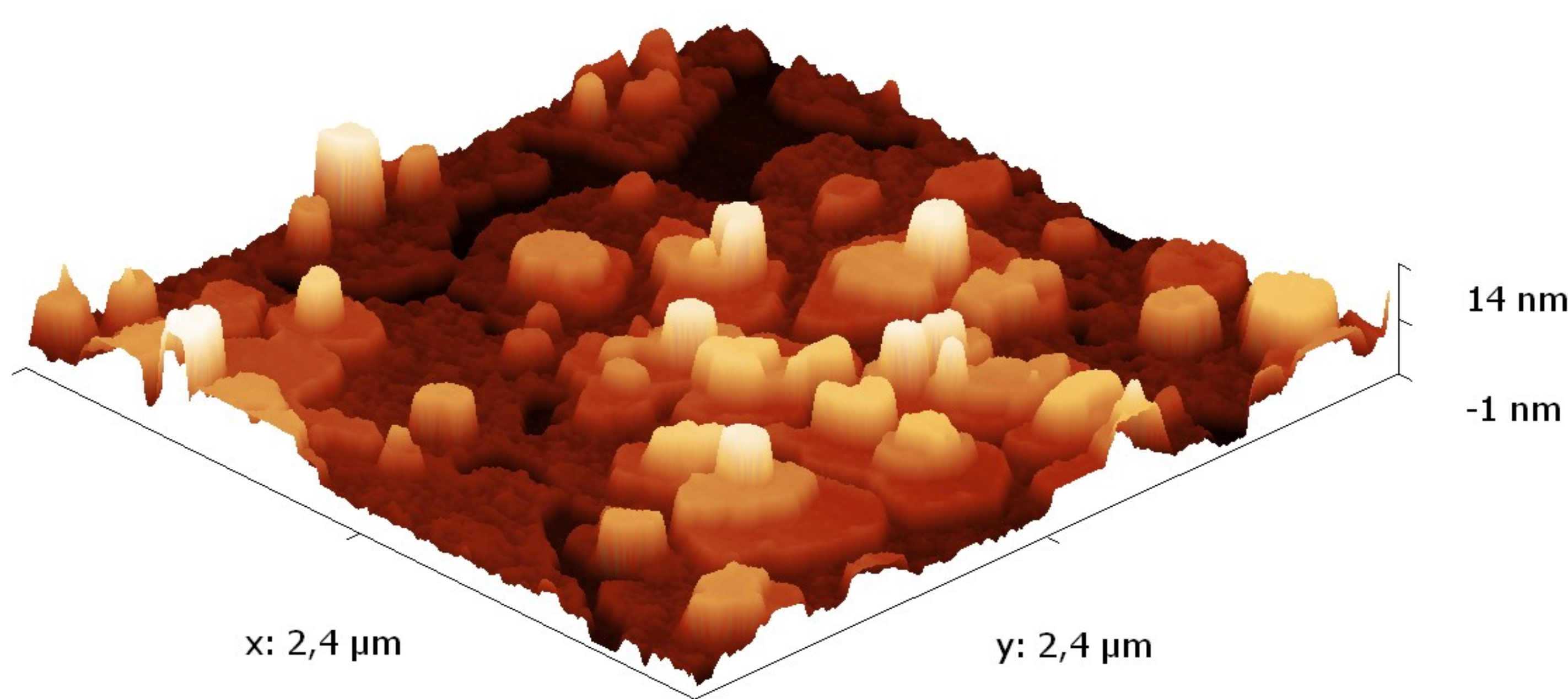


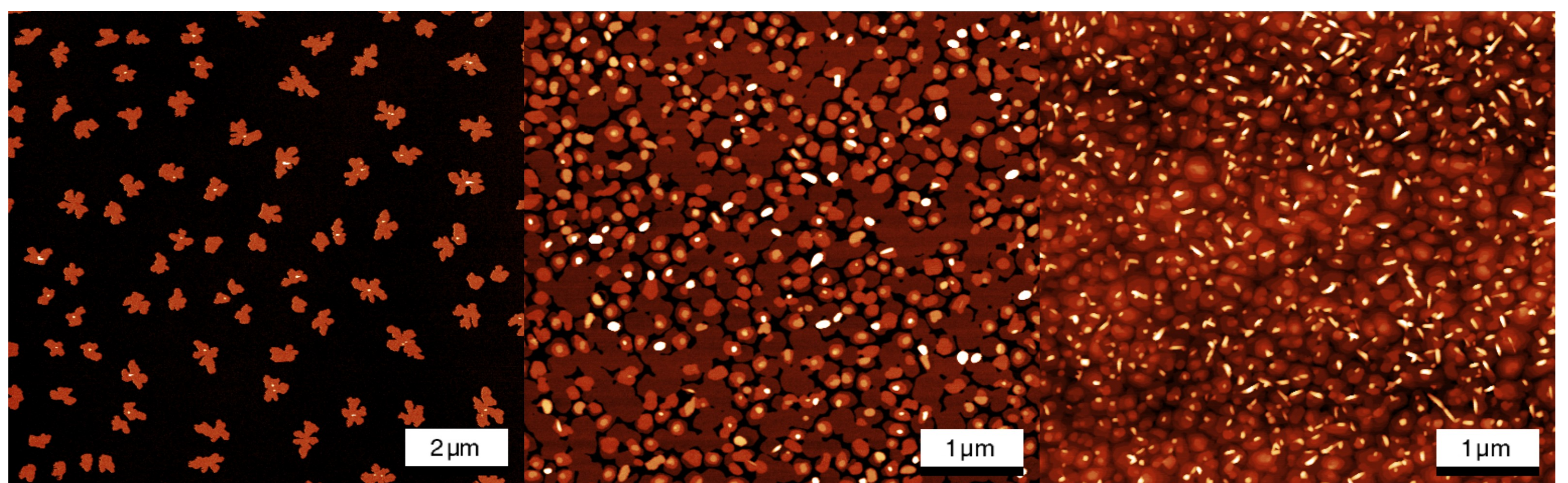
Organic thin film growth processes

Investigations of the molecular diffusion processes during the epitaxial growth by scanning probe techniques.



Organic semiconductors have attracted interest due to their great potential in advanced electronic devices. The device performance is determined by the properties of the active organic layer. An enhanced numerical analysis of the AFM data reveals information which connects growth parameters and thin film properties.

- Growth in Ultra High Vacuum
- AFM-studies of surface morphology
- Comparison with simulations
- The project is part of the Austrian Science Fund's national research network: "*Interface controlled and functionalised organic films*".



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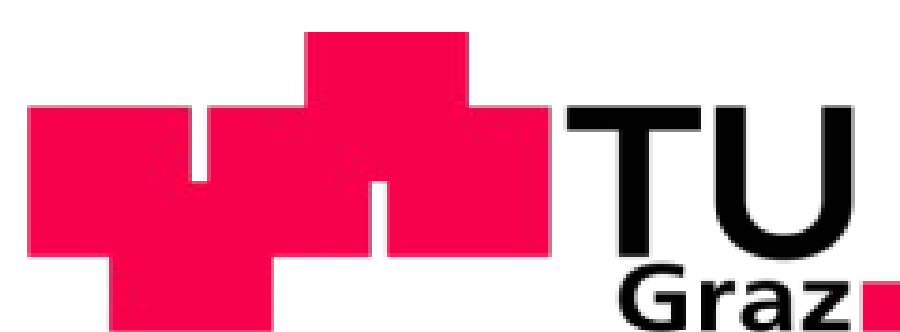
Personal data:

Master's degree in technical physics (TU Graz), since January 2009 PhD student under supervision of Prof. Christian Teichert within a project funded by the Austrian Science Fund **FWF** Der Wissenschaftsfonds. 2007/08 research trips to the State University of St.Petersburg Russia

Collaborations:

Chair of Atomistic Modelling and Design of Materials (at MUL)

and



Main research:

- Study of the growth morphologies (OMBE+HWE) of organic semiconductor layers with Atomic Force Microscopy (AFM) and Low Energy Electron Microscopy (LEEM)
- Monte Carlo simulations of the molecular growth processes